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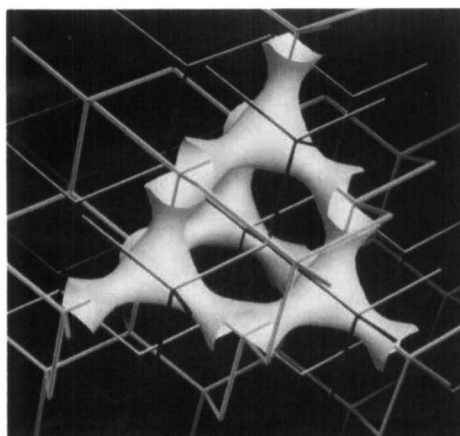
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ON THE COVER: The cover shows a computer-generated image of a surface representing the highly ordered microphase separated morphology of a block copolymer. This surface is of constant mean curvature and is a member of the family of mathematical surfaces which includes the classical Schwarz *D* surface. The inset shows a digitized bright-field TEM image (left half) of the microdomain morphology of a polystyrene-polyisoprene star block copolymer alongside the computer-simulated [111] projection of the model structure whose PS/PI interface is the computer-generated image described above. See "Observation of Defects in Crystalline Polymers by HREM" by D.C. Martin and E.L. Thomas in this issue.

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A. Golanski
Centre National d'Études des
Télécommunications
CNS-RPT
Chemin du Vieux Chêne
BP 98
38243 Meylan Cedex
France
(33) 76 51 40 67

Editor

G. A. Oare
(412) 367-3036

Assistant Editor

F. M. Wieloch
(412) 367-3036

Design/Production

C. Love
(412) 367-3003

Editorial Assistant

J. Dininny
(412) 367-3036

Guest Editor:

E. L. Thomas

Advertising and Circulation

M. E. Kaufold
(412) 367-3036

MRS BULLETIN EDITORIAL BOARD

MINKO BALKANSKI
University of Pierre and Marie Curie
Laboratoire de Physique des Solides
4 Place Jussieu, Tour 13
75230 Paris Cedex 05, France
telephone: 336-25-25

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9700 South Cass Avenue
Argonne, IL 60439
telephone: (312) 972-4925

SHU-EN HSU
Director
Materials R&D Center
Chung Shan Institute of
Science and Technology
P.O. Box 1-26
Lung-Tan, Taiwan, China
Cable: CHUNSHANINST SHIMEN,
TAIWAN

RALPH J. JACCODINE
Sherman Fairchild Professor
of Solid State Studies
Sherman Fairchild Laboratory 161
Lehigh University
Bethlehem, PA 18015
telephone: (215) 862-3950

HIROSHI KAMIMURA
Department of Physics
Faculty of Science
University of Tokyo
7-3-1 Hongo, Bunkyo-ku
Tokyo 113 Japan
telephone: 03-812-2111
telex: UTPHYSIC J23472

ELTON N. KAUFMANN (Chairman)
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Osaka, Japan 560

JULIA M. PHILLIPS
AT&T Bell Laboratories
Room 1E-431
600 Mountain Avenue
Murray Hill, NJ 07974
telephone: (201) 582-4428

EMANUELE RIMINI
University of Catania
Department of Physics
57 Corso Italia
I 95129 Catania, Italy
telephone: 37-70-61
telex: 911554 INFUNCT I

RUSTUM ROY
Materials Research Laboratory
Pennsylvania State University
University Park, PA 16802
telephone: (814) 865-3424

RICHARD L. SCHWOEBEL
Directorate 1800
Sandia National Laboratories
P.O. Box 5800
Albuquerque, NM 87185
telephone: (505) 844-9273

G. D. W. SMITH
University of Oxford
Department of Metallurgy
and Science of Materials
Parks Road
Oxford OX1 3PH, England

TAKUO SUGANO
Professor of Engineering
Department of Electronic Engineering
University of Tokyo
7-3-1 Hongo, Bunkyo-ku
Tokyo 113 Japan
telephone: 03-812-2111, ext. 6675

C. W. WHITE
Solid State Division
Oak Ridge National Laboratory
Oak Ridge, TN 37831
telephone: (615) 574-6295

J. S. WILLIAMS
Royal Melbourne Institute of Technology
Microelectronics Tech. Center
124 Latrobe Street
Melbourne, Victoria 3000, Australia
telephone: 03-660-2459

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The Materials Research Society (MRS) is a nonprofit scientific association founded in 1973 to promote interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 5,900 scientists from industrial, government, and university research laboratories in the United States and more than 25 countries.

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Mk II Specifications

Dynamic Mechanical Thermal Analyser

Dynamic Mechanical

FREQUENCIES

16 freq. in the range 0.01 to 200 Hz
0.01, 0.02, 0.03, 0.1, 0.2, 0.3, 1, 2, 3, 5, 10, 20, 30, 50, 100, 200 Hz
Selected by push button or remotely by computer

MODULUS RANGE

Young's 10^6 N/m² - 10^{11} N/m²
Rigidity 10^3 N/m² - 5×10^8 N/m²
Tensile 10^6 N/m² - 10^{11} N/m²
Accuracy depends on optimizing clamping

DAMPING RANGE

Tan δ 0.0001 - 9.999

RESOLUTION

On Tan δ 0.0001

MEASUREMENT MODES

YOUNG'S MODULUS - bending of double or single cantilever (bar specimen length range 1.8-4.6 cm, thickness range 0.1-3.0 mm, maximum breadth 1.8 cm).

RIGIDITY MODULUS, shear sandwich (cross-section typically 1 cm², thickness 0.3 cm).

TENSILE (typically, length 1 cm, cross-section 0.01 cm²).

DISPLACEMENT

10 different strains covering a 20 times range.
(Minimum 0.01 mm; maximum 0.25 mm)
Selected by push button or remotely by computer.

Thermal Control

CONTROL AND MEASUREMENT

Platinum resistance sensor placed 1 mm from sample surface

TEMPERATURE RANGE

-150°C to +500°C

SCAN RATES

Heating 1°C/10 min to 20°C/min
Cooling 1°C/10 min to 15°C/min
Resolution 0.1°C over whole range

ACCURACY

Sample temperature normally within 1°C of indicated temperature for scan rates up to 5°C/min.

MODES

Heat, Cool, Cycle.
Isothermal hold at any point. Front panel selection or remotely controlled.

COMPUTER CONTROL

IEEE interface, full software control.



POLYMER LABORATORIES



Polymer Laboratories Ltd. The Technology Centre, Epinal Way,

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Polymer Laboratories Inc. Amherst Fields Research Park, Amherst,

MA 01002, U.S.A. Tel: (413) 253-9554.

Polymer Laboratories published online by Cambridge University Press

6900 Heidelberg, West Germany. Tel: 06221 - 20090

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